



DE-64 Camera System

the ultimate direct detector for high-end TEMs

Direct Electron delivers | bigger | better | faster | cameras for electron microscopy

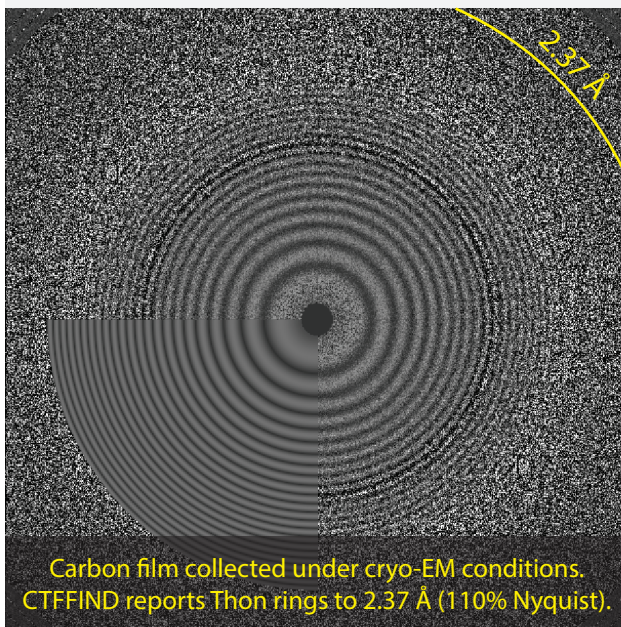
Better Science, Faster – Brilliant Results in Less Time

- Direct detection device (DDD®) delivers *high resolution and excellent sensitivity*.
- **8k × 8k** (67.1 million) pixels!
- Capture >4× more area in each image. Complete experiments >4× faster.
- **High-speed** continuous streaming for “movie-mode” processing (e.g., motion correction) and continuous-tilt tomography.
- **Unrivalled features:** integrated survey sensor & Faraday plate.
- **Electron counting** to maximize signal-to-noise ratio when needed.
- **The best of all the new TEM camera technology in a single integrated system.**
- Low total cost-of-ownership and exceptional support.

Microscopy
TODAY
INNOVATION AWARDS

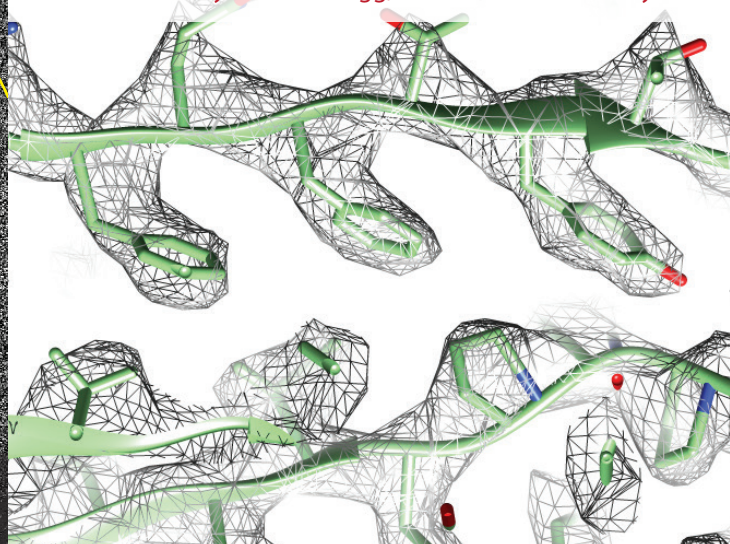


Direct Electron®
INNOVATION PROPELLING DISCOVERY



Carbon film collected under cryo-EM conditions. CTFIND reports Thon rings to 2.37 Å (110% Nyquist).

Cryo-EM of AAV at 2.8 Å resolution (~85% Nyquist).
Courtesy of Scott Staggs, Florida State University.

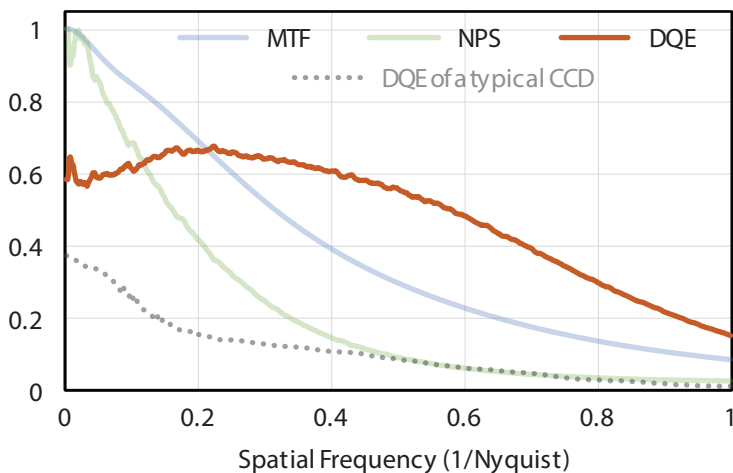


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| | |
|-----------------------------------|---|
| detection electron energy | optimized for 80 keV – 1.25 MeV |
| pixel array specification | 8192 × 8192 (67.1 million pixels) 6.5 μm pixel pitch |
| single electron SNR | ~50:1 (300 kV) |
| sensor design | >3T pixel design with correlated double sampling (CDS) backthinned radiation hardened |
| acquisition frame rate | 30 fps max, unbinned full-frame subarray readout up to 1920 fps max |
| acquisition modes | integrating mode counting mode (with optional counting system) |
| exposure rate | large dynamic range with consistent performance in integrating mode (e.g., 4 – 400 e-/pixel/s) |
| mounting position | fully retractable mounted on-axis TEM bottom port or in JEOL film drawer |
| “buddy” camera | integrated near-axis 2048 × 2048 scintillator-coupled survey sensor |
| exposure measurement | integrated Faraday plate for exposure measurement with each acquisition |
| sensor protection | integrated physical protection shutter microscope blanking/shuttering failsafe software |
| computer system | certified high-performance computer system with large >25 TB RAID array for data streaming |
| image format | image data stored in non-proprietary format to ensure broad compatibility |
| acquisition & processing software | <i>conventional acquisition:</i> DE-IM (full-featured, user-friendly) μManager (free, open-source) <i>in situ movie acquisition:</i> DE-StreamPix (continuous streaming) <i>automated acquisition:</i> Leginon SerialEM EMTTools (TVIPS) others using the DE SDK <i>“movie” processing:</i> DE image processing software (free, open-source, Python-based) others <i>customization:</i> software development kit (SDK) for integration with custom software |

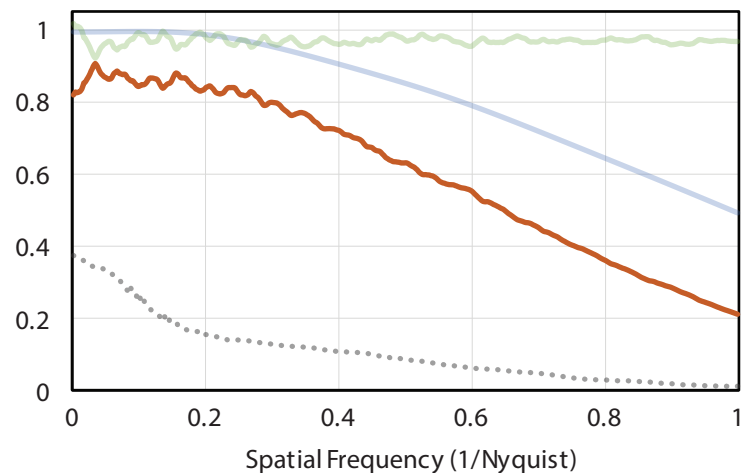
Integrating Mode

best for maximizing overall productivity



Electron Counting Mode

best for maximizing signal-to-noise ratio



* Note: Specifications and performance are subject to change.



there is
much more...

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